

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination EDMONSON ET AL.	
		09/909,969	Examiner	Art Unit
		Sudhanshu C. Pathak	2634	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,462,698	10-2002	Campbell et al.	342/51
	B	US-6,556,146	04-2003	Ruile et al.	340/870.3
	C	US-5,289,160	02-1994	Fiorletta, Carl A.	340/447
	D	US-5,691,698	11-1997	Scholl et al.	340/572.5
	E	US-6,717,983	04-2004	Toda, Kohji	375/222
	F	US-4,625,208	11-1986	Skeie et al.	342/51
	G	US-5,469,170	11-1995	Mariani, Elio A.	342/51
	H	US-6,455,979	09-2002	Reindl et al.	310/313D
	I	US-5,610,566	03-1997	Chen et al.	333/194
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ostermayer, G.; On the Noise Behavior of a SAW Convolver Used as a Matched Filter; IEEE Transcations on Microwave Theory and Techniques; Vol. 49, No. 4; April 2001; Pages 779-786.
	V	Steindl, R. et al.; Impedence Loaded SAW Sensors Offer Wide Range of Measurement Opportunities; IEEE Transcations on Microwave Theory and Techniques; Vol. 47, No. 12; December 1999; Pages 2625-2629
	W	Steindl, R. et al.; SAW delay lines for wirelessly requastable conventional sensors; IEEE Ultrasonics Symposium; 1998; Pages 351-354
	X	Reindl, L. et al.; Programmable Reflectors for SAW-ID Tags; IEEE Ultrasonics Symposium; 1993; Pages 125-130

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.